Digest of Tech. Papers The 11th Conf. (1979 International) on Solid State Devices, Tokyo

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A Coupled-Waveguide TE/TM Mode Splitter Osamu Mikami

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A guided-wave optical TE/TM mode splitter is one of the basic components for integrated optical circuits. This paper proposes a novel channel waveguided TE/TM mode splitter, which spatially separates the TE and TM mode components, and which is compatible with single mode fiber systems.

The device configuration is shown in Fig. 1. Two straight waveguides are formed closely parallel to each other on an electro-optic c-plate  $\text{LiNbO}_3$ substrate by preferential Ti diffusion. The interaction length is denoted by L<sub>1</sub>. An Al metal strip is loaded on waveguide 2. Two planar electrodes, whose lengths L<sub>2</sub> are equal to L<sub>1</sub>/2, are formed on waveguide 1 with an in-between Al<sub>2</sub>O<sub>3</sub> buffer layer. The following condition is assumed to be satisfied for the TE mode :

 $L_0 \leq L_1 \leq 3L_0$ , (1) where L is 0 dB coupling length. This condition is not required for the TM mode. From coupled wave equations, 1) light coupling between two adjacent waveguides can be made negligibly small, if  $L_0 | \beta_1 - \beta_2 | \gg 1$  is satisfied, where  $\beta_1$  and  $\beta_2$ are propagation constants for the two waveguides. A metal film loaded on a waveguide markedly reduces the TM mode propagation constant.<sup>2)</sup> A simple calculation for an Al loaded slab waveguide shows that the TM mode propagation constant changes by nearly 0.03 %, which is large enough to reduce TM mode light coupling to zero and realize 20 dB crosstalk for  $L_{o} \gtrsim$  10 mm. On the other hand, the TE mode propagation constant change, due to the loaded metal film, is much smaller, so that light coupling takes place. From the condition of Eq. ( 1 ), a complete 0 dB coupling can be realized by applying external voltages  $V_1$  and  $V_2$  to the two electrodes.<sup>3)</sup> Applied voltages  $V_1$  and  $V_2$  have an opposite sign with respect to each other. As a result, when a laser beam is fed into waveguide 1, the TM mode component passes through the waveguide (" straight-through state "). On the other hand, the TE mode component is coupled to waveguide 2 (" crossover state ").

The device structure was as follows : Each waveguide was 8  $\mu$ m wide, the gap width was 5  $\mu$ m and the interaction length L<sub>1</sub> was 15 mm. 0 dB coupling lengths for the TM and TE modes were measured, at 1.15  $\mu$ m wavelength, to be about 10 mm and 7.5 mm, respectively. The loaded Al strip on waveguide 2 was about 2000 Å thick. After depositing about 1700 Å thick Al<sub>2</sub>O<sub>3</sub> fim on waveguide 1, two planar Al electrodes, with 7.5 mm length L<sub>2</sub>, were provided. The gap between these

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electrodes and the metal strip on waveguide 2 was 5 µm.

The 1.15  $\mu$ m He-Ne laser beam was coupled into waveguide 1 with a single mode fiber. Only fundamental TM and TE modes propagated in the waveguides. At zero applied voltages  $V_1=V_2=0$ , light coupling for the TM mode was almost completely reduced to zero, and more than 20 dB crosstalk was realized. This was due to sufficiently large propagation constant difference induced by the loaded A1 strip. On the other hand, nearly 25 % coupling occured for the TE mode at  $V_1=V_2$ =0. Next, the  $V_1$  and  $V_2$  values were adjusted so that the TE mode output power from waveguide 2 became a maximum. In this sample, the " crossover state " was realized at  $V_1=20$  V and  $V_2=-15$  V. The obtained TE mode crosstalk was about 20 dB. The " straight-through state " for the TM mode was hardly affected by the applied voltage. The near-field patterns of the waveguides were measured by using a galvano-mirror. As shown in Fig. 2, " straight-through state " for the TM mode and " crossover state " for the TE mode were simultaneously realized. Optical insertion loss, excluding fiber to waveguide connecting loss and Fresnel reflection loss at the device end faces, was 1.7 dB.



References

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Fig. 1 Principal configuration of the proposed TE/TM mode splitter.

Fig. 2 Observed near-field patterns
for TM and TE modes at V<sub>1</sub>=V<sub>2</sub>=0,
and V<sub>1</sub>=20 V, V<sub>2</sub>=-15 V. The laser
beam was coupled into waveguide 1.

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